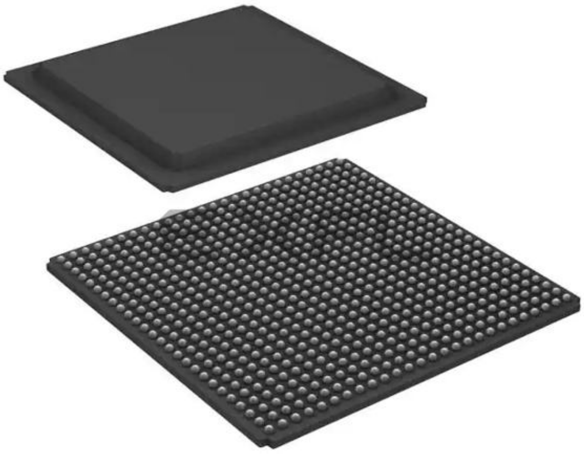
AMD Xilinx - XCV800-5FG676I Datasheet



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Understanding Embedded - FPGAs (Field Programmable Gate Array)

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Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details	
Product Status	Obsolete
Number of LABs/CLBs	4704
Number of Logic Elements/Cells	21168
Total RAM Bits	114688
Number of I/O	444
Number of Gates	888439
Voltage - Supply	2.375V ~ 2.625V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	676-BGA
Supplier Device Package	676-FBGA (27x27)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xcv800-5fg676i

Virtex™ 2.5 V Field Programmable Gate Arrays

DS003-2 (v4.0) March 1, 2013

Product Specification

Architectural Description

Virtex Array

The Virtex user-programmable gate array, shown in Figure 1, comprises two major configurable elements: configurable logic blocks (CLBs) and input/output blocks (IOBs).

- CLBs provide the functional elements for constructing logic
- IOBs provide the interface between the package pins and the CLBs

CLBs interconnect through a general routing matrix (GRM). The GRM comprises an array of routing switches located at the intersections of horizontal and vertical routing channels. Each CLB nests into a VersaBlock™ that also provides local routing resources to connect the CLB to the GRM.

The VersaRing™ I/O interface provides additional routing resources around the periphery of the device. This routing improves I/O routability and facilitates pin locking.

The Virtex architecture also includes the following circuits that connect to the GRM.

- Dedicated block memories of 4096 bits each
- Clock DLLs for clock-distribution delay compensation and clock domain control
- 3-State buffers (BUFTs) associated with each CLB that drive dedicated segmentable horizontal routing resources

Values stored in static memory cells control the configurable logic elements and interconnect resources. These values load into the memory cells on power-up, and can reload if necessary to change the function of the device.

Input/Output Block

The Virtex IOB, Figure 2, features SelectIO™ inputs and outputs that support a wide variety of I/O signalling standards, see Table 1.

The three IOB storage elements function either as edge-triggered D-type flip-flops or as level sensitive latches. Each IOB has a clock signal (CLK) shared by the three flip-flops and independent clock enable signals for each flip-flop.

In addition to the CLK and CE control signals, the three flip-flops share a Set/Reset (SR). For each flip-flop, this signal can be independently configured as a synchronous Set, a synchronous Reset, an asynchronous Preset, or an asynchronous Clear.

The output buffer and all of the IOB control signals have independent polarity controls.

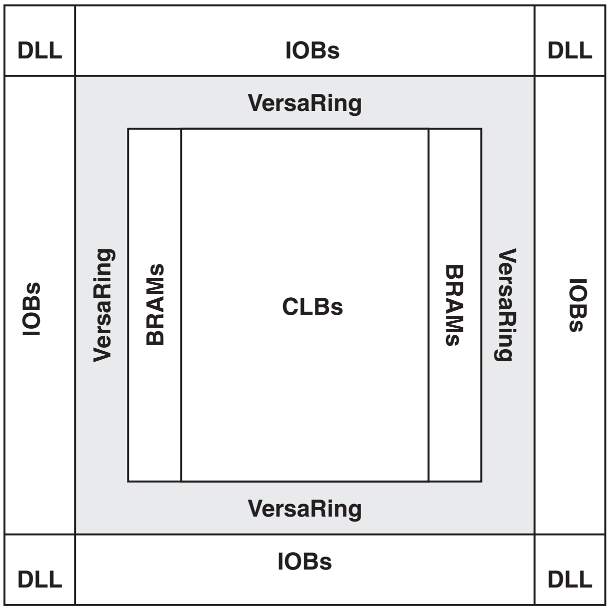

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Figure 1: **Virtex Architecture Overview**

All pads are protected against damage from electrostatic discharge (ESD) and from over-voltage transients. Two forms of over-voltage protection are provided, one that permits 5 V compliance, and one that does not. For 5 V compliance, a Zener-like structure connected to ground turns on when the output rises to approximately 6.5 V. When PCI 3.3 V compliance is required, a conventional clamp diode is connected to the output supply voltage, V_{CCO}.

Optional pull-up and pull-down resistors and an optional weak-keeper circuit are attached to each pad. Prior to configuration, all pins not involved in configuration are forced into their high-impedance state. The pull-down resistors and the weak-keeper circuits are inactive, but inputs can optionally be pulled up.

The activation of pull-up resistors prior to configuration is controlled on a global basis by the configuration mode pins. If the pull-up resistors are not activated, all the pins will float. Consequently, external pull-up or pull-down resistors must be provided on pins required to be at a well-defined logic level prior to configuration.

All Virtex IOBs support IEEE 1149.1-compatible boundary scan testing.

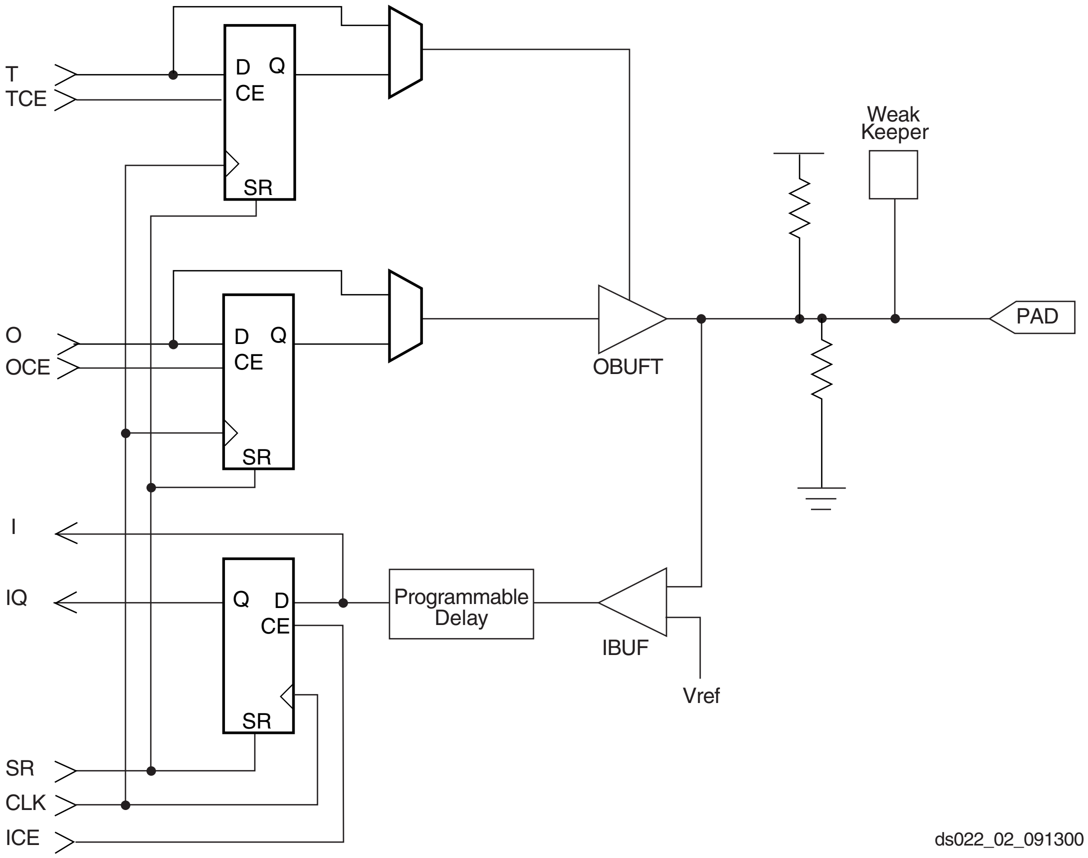

Figure 2: **Virtex Input/Output Block (IOB)**

Table 1: **Supported Select I/O Standards**

I/O Standard	Input Reference Voltage (V_{REF})	Output Source Voltage (V_{CCO})	Board Termination Voltage (V_{TT})	5 V Tolerant
LVTTL 2 – 24 mA	N/A	3.3	N/A	Yes
LVCMOS2	N/A	2.5	N/A	Yes
PCI, 5 V	N/A	3.3	N/A	Yes
PCI, 3.3 V	N/A	3.3	N/A	No
GTL	0.8	N/A	1.2	No
GTL+	1.0	N/A	1.5	No
HSTL Class I	0.75	1.5	0.75	No
HSTL Class III	0.9	1.5	1.5	No
HSTL Class IV	0.9	1.5	1.5	No
SSTL3 Class I &II	1.5	3.3	1.5	No
SSTL2 Class I & II	1.25	2.5	1.25	No
CTT	1.5	3.3	1.5	No
AGP	1.32	3.3	N/A	No

Input Path

A buffer In the Virtex IOB input path routes the input signal either directly to internal logic or through an optional input flip-flop.

An optional delay element at the D-input of this flip-flop eliminates pad-to-pad hold time. The delay is matched to the internal clock-distribution delay of the FPGA, and when used, assures that the pad-to-pad hold time is zero.

Each input buffer can be configured to conform to any of the low-voltage signalling standards supported. In some of these standards the input buffer utilizes a user-supplied threshold voltage, V_{REF}. The need to supply V_{REF} imposes constraints on which standards can used in close proximity to each other. See **I/O Banking**, page 3.

There are optional pull-up and pull-down resistors at each user I/O input for use after configuration. Their value is in the range 50 kΩ – 100 kΩ.

Output Path

The output path includes a 3-state output buffer that drives the output signal onto the pad. The output signal can be routed to the buffer directly from the internal logic or through an optional IOB output flip-flop.

The 3-state control of the output can also be routed directly from the internal logic or through a flip-flip that provides synchronous enable and disable.

Each output driver can be individually programmed for a wide range of low-voltage signalling standards. Each output buffer can source up to 24 mA and sink up to 48mA. Drive strength and slew rate controls minimize bus transients.

In most signalling standards, the output High voltage depends on an externally supplied V_{CCO} voltage. The need to supply V_{CCO} imposes constraints on which standards can be used in close proximity to each other. See **I/O Banking**, page 3.

An optional weak-keeper circuit is connected to each output. When selected, the circuit monitors the voltage on the pad and weakly drives the pin High or Low to match the input signal. If the pin is connected to a multiple-source signal, the weak keeper holds the signal in its last state if all drivers are disabled. Maintaining a valid logic level in this way eliminates bus chatter.

Because the weak-keeper circuit uses the IOB input buffer to monitor the input level, an appropriate V_{REF} voltage must be provided if the signalling standard requires one. The provision of this voltage must comply with the I/O banking rules.

I/O Banking

Some of the I/O standards described above require V_{CCO} and/or V_{REF} voltages. These voltages externally and connected to device pins that serve groups of IOBs, called banks. Consequently, restrictions exist about which I/O standards can be combined within a given bank.

Eight I/O banks result from separating each edge of the FPGA into two banks, as shown in Figure 3. Each bank has multiple V_{CCO} pins, all of which must be connected to the same voltage. This voltage is determined by the output standards in use.

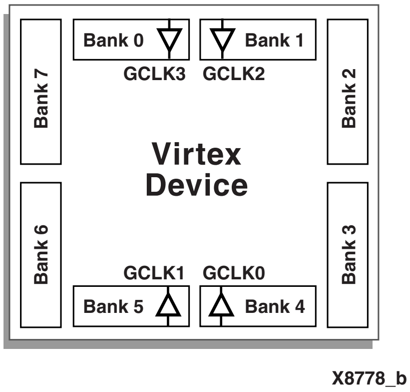

Figure 3: **Virtex I/O Banks**

Within a bank, output standards can be mixed only if they use the same V_{CCO}. Compatible standards are shown in Table 2. GTL and GTL+ appear under all voltages because their open-drain outputs do not depend on V_{CCO}.

Table 2: **Compatible Output Standards**

V_{CCO}	Compatible Standards
3.3 V	PCI, LVTTL, SSTL3 I, SSTL3 II, CTT, AGP, GTL, GTL+
2.5 V	SSTL2 I, SSTL2 II, LVCMOS2, GTL, GTL+
1.5 V	HSTL I, HSTL III, HSTL IV, GTL, GTL+

Some input standards require a user-supplied threshold voltage, V_{REF}. In this case, certain user-I/O pins are automatically configured as inputs for the V_{REF} voltage. Approximately one in six of the I/O pins in the bank assume this role.

The V_{REF} pins within a bank are interconnected internally and consequently only one V_{REF} voltage can be used within each bank. All V_{REF} pins in the bank, however, must be connected to the external voltage source for correct operation.

Within a bank, inputs that require V_{REF} can be mixed with those that do not. However, only one V_{REF} voltage can be used within a bank. Input buffers that use V_{REF} are not 5 V tolerant. LVTTL, LVCMOS2, and PCI 33 MHz 5 V, are 5 V tolerant.

The V_{CCO} and V_{REF} pins for each bank appear in the device Pinout tables and diagrams. The diagrams also show the bank affiliation of each I/O.

Within a given package, the number of V_{REF} and V_{CCO} pins can vary depending on the size of device. In larger devices,

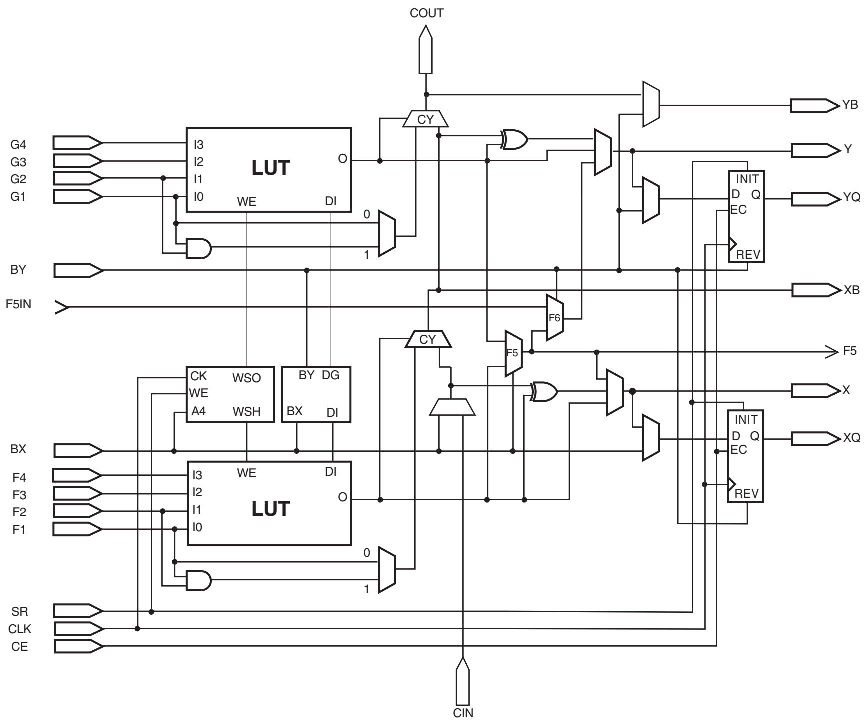

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Figure 5: **Detailed View of Virtex Slice**

Additional Logic

The F5 multiplexer in each slice combines the function generator outputs. This combination provides either a function generator that can implement any 5-input function, a 4:1 multiplexer, or selected functions of up to nine inputs.

Similarly, the F6 multiplexer combines the outputs of all four function generators in the CLB by selecting one of the F5-multiplexer outputs. This permits the implementation of any 6-input function, an 8:1 multiplexer, or selected functions of up to 19 inputs.

Each CLB has four direct feedthrough paths, one per LC. These paths provide extra data input lines or additional local routing that does not consume logic resources.

Arithmetic Logic

Dedicated carry logic provides fast arithmetic carry capability for high-speed arithmetic functions. The Virtex CLB supports two separate carry chains, one per Slice. The height of the carry chains is two bits per CLB.

The arithmetic logic includes an XOR gate that allows a 1-bit full adder to be implemented within an LC. In addition, a dedicated AND gate improves the efficiency of multiplier implementation.

The dedicated carry path can also be used to cascade function generators for implementing wide logic functions.

BUFTs

Each Virtex CLB contains two 3-state drivers (BUFTs) that can drive on-chip busses. See **Dedicated Routing**, page 7. Each Virtex BUFT has an independent 3-state control pin and an independent input pin.

Block SelectRAM

Virtex FPGAs incorporate several large block SelectRAM memories. These complement the distributed LUT SelectRAMs that provide shallow RAM structures implemented in CLBs.

Block SelectRAM memory blocks are organized in columns. All Virtex devices contain two such columns, one along each vertical edge. These columns extend the full height of the chip. Each memory block is four CLBs high, and consequently, a Virtex device 64 CLBs high contains 16 memory blocks per column, and a total of 32 blocks.

Table 3 shows the amount of block SelectRAM memory that is available in each Virtex device.

Table 3: **Virtex Block SelectRAM Amounts**

Device	# of Blocks	Total Block SelectRAM Bits
XCV50	8	32,768
XCV100	10	40,960
XCV150	12	49,152
XCV200	14	57,344
XCV300	16	65,536
XCV400	20	81,920
XCV600	24	98,304
XCV800	28	114,688
XCV1000	32	131,072

Each block SelectRAM cell, as illustrated in Figure 6, is a fully synchronous dual-ported 4096-bit RAM with independent control signals for each port. The data widths of the two ports can be configured independently, providing built-in bus-width conversion.

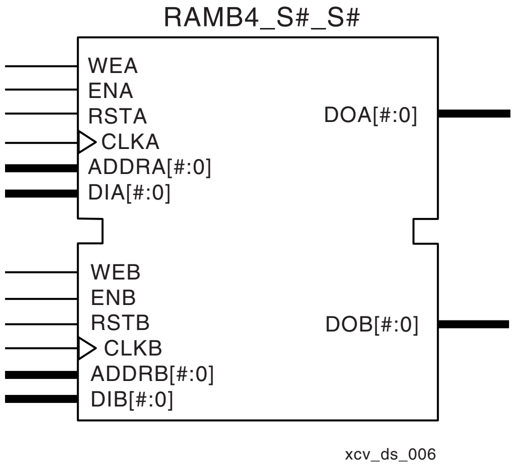


Figure 6: **Dual-Port Block SelectRAM**

Table 4 shows the depth and width aspect ratios for the block SelectRAM.

Table 4: **Block SelectRAM Port Aspect Ratios**

Width	Depth	ADDR Bus	Data Bus
1	4096	ADDR<11:0>	DATA<0>
2	2048	ADDR<10:0>	DATA<1:0>
4	1024	ADDR<9:0>	DATA<3:0>
8	512	ADDR<8:0>	DATA<7:0>
16	256	ADDR<7:0>	DATA<15:0>

The Virtex block SelectRAM also includes dedicated routing to provide an efficient interface with both CLBs and other block SelectRAMs. Refer to XAPP130 for block SelectRAM timing waveforms.

Programmable Routing Matrix

It is the longest delay path that limits the speed of any worst-case design. Consequently, the Virtex routing architecture and its place-and-route software were defined in a single optimization process. This joint optimization minimizes long-path delays, and consequently, yields the best system performance.

The joint optimization also reduces design compilation times because the architecture is software-friendly. Design cycles are correspondingly reduced due to shorter design iteration times.

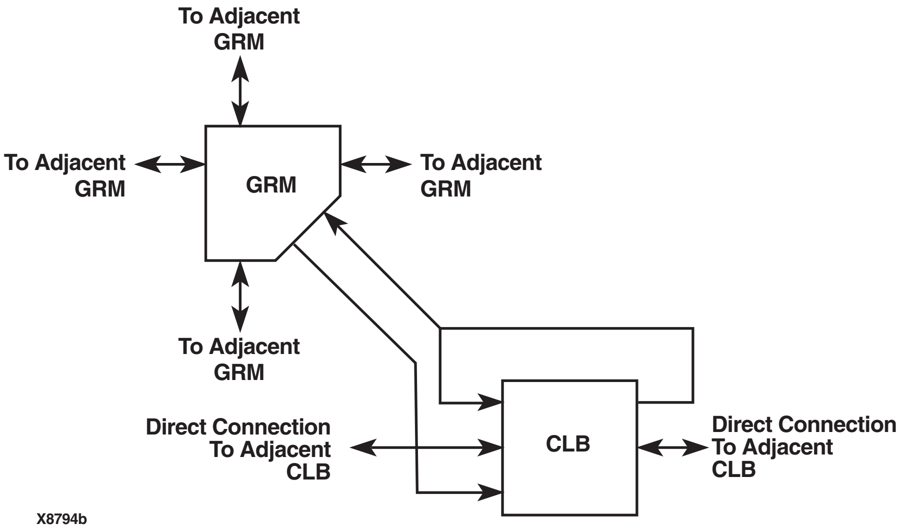


Figure 7: **Virtex Local Routing**

Local Routing

The VersaBlock provides local routing resources, as shown in Figure 7, providing the following three types of connections.

- Interconnections among the LUTs, flip-flops, and GRM
- Internal CLB feedback paths that provide high-speed connections to LUTs within the same CLB, chaining them together with minimal routing delay
- Direct paths that provide high-speed connections between horizontally adjacent CLBs, eliminating the delay of the GRM.

Four dedicated clock pads are provided, one adjacent to each of the global buffers. The input to the global buffer is selected either from these pads or from signals in the general purpose routing.

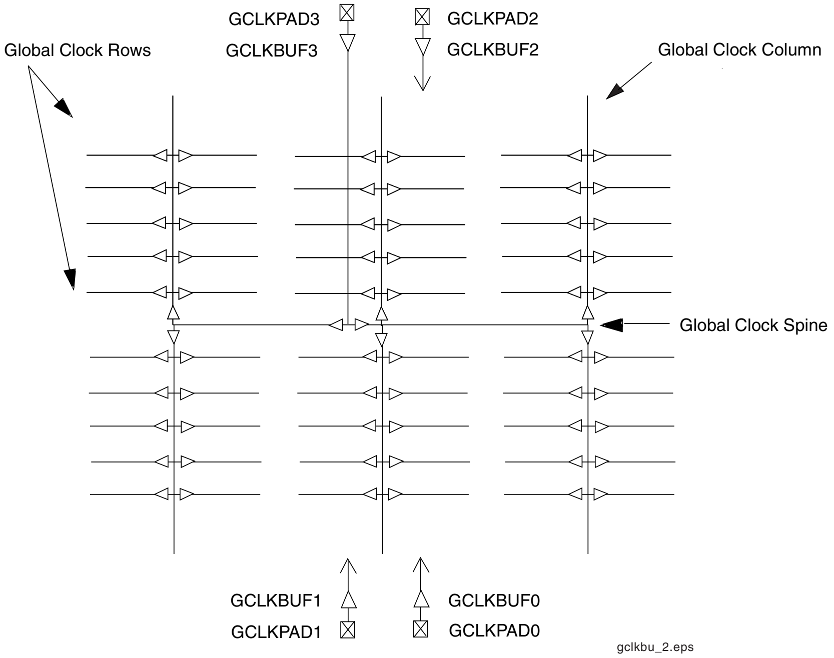


Figure 9: **Global Clock Distribution Network**

Delay-Locked Loop (DLL)

Associated with each global clock input buffer is a fully digital Delay-Locked Loop (DLL) that can eliminate skew between the clock input pad and internal clock-input pins throughout the device. Each DLL can drive two global clock networks.The DLL monitors the input clock and the distributed clock, and automatically adjusts a clock delay element. Clock edges reach internal flip-flops one to four clock periods after they arrive at the input. This closed-loop system effectively eliminates clock-distribution delay by ensuring that clock edges arrive at internal flip-flops in synchronism with clock edges arriving at the input.

In addition to eliminating clock-distribution delay, the DLL provides advanced control of multiple clock domains. The DLL provides four quadrature phases of the source clock, can double the clock, or divide the clock by 1.5, 2, 2.5, 3, 4, 5, 8, or 16.

The DLL also operates as a clock mirror. By driving the output from a DLL off-chip and then back on again, the DLL can be used to de-skew a board level clock among multiple Virtex devices.

In order to guarantee that the system clock is operating correctly prior to the FPGA starting up after configuration, the DLL can delay the completion of the configuration process until after it has achieved lock.

See **DLL Timing Parameters**, page 21 of Module 3, for frequency range information.

Boundary Scan

Virtex devices support all the mandatory boundary-scan instructions specified in the IEEE standard 1149.1. A Test Access Port (TAP) and registers are provided that implement the EXTEST, INTEST, SAMPLE/PRELOAD, BYPASS, IDCODE, USERCODE, and HIGHZ instructions. The TAP also supports two internal scan chains and configuration/readback of the device.The TAP uses dedicated package pins that always operate using LVTTL. For TDO to operate using LVTTL, the V_{CCO} for Bank 2 should be 3.3 V. Otherwise, TDO switches rail-to-rail between ground and V_{CCO}.

Boundary-scan operation is independent of individual IOB configurations, and unaffected by package type. All IOBs, including un-bonded ones, are treated as independent 3-state bidirectional pins in a single scan chain. Retention of the bidirectional test capability after configuration facilitates the testing of external interconnections, provided the user design or application is turned off.

Table 5 lists the boundary-scan instructions supported in Virtex FPGAs. Internal signals can be captured during EXTEST by connecting them to un-bonded or unused IOBs. They can also be connected to the unused outputs of IOBs defined as unidirectional input pins.

Before the device is configured, all instructions except USER1 and USER2 are available. After configuration, all instructions are available. During configuration, it is recommended that those operations using the boundary-scan register (SAMPLE/PRELOAD, INTEST, EXTEST) not be performed.

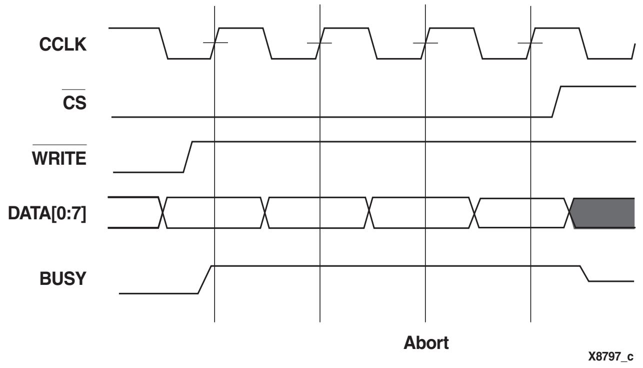


Figure 18: **SelectMAP Write Abort Waveforms**

Boundary-Scan Mode

In the boundary-scan mode, configuration is done through the IEEE 1149.1 Test Access Port. Note that the $\overline{\text{PROGRAM}}$ pin must be pulled High prior to reconfiguration. A Low on the $\overline{\text{PROGRAM}}$ pin resets the TAP controller and no JTAG operations can be performed.

Configuration through the TAP uses the CFG_IN instruction. This instruction allows data input on TDI to be converted into data packets for the internal configuration bus.

The following steps are required to configure the FPGA through the boundary-scan port (when using TCK as a start-up clock).

1. Load the CFG_IN instruction into the boundary-scan instruction register (IR)
2. Enter the Shift-DR (SDR) state
3. Shift a configuration bitstream into TDI
4. Return to Run-Test-Idle (RTI)
5. Load the JSTART instruction into IR
6. Enter the SDR state
7. Clock TCK through the startup sequence
8. Return to RTI

Configuration and readback via the TAP is always available. The boundary-scan mode is selected by a <101> or 001> on the mode pins (M2, M1, M0). For details on TAP characteristics, refer to XAPP139.

Configuration Sequence

The configuration of Virtex devices is a three-phase process. First, the configuration memory is cleared. Next, configuration data is loaded into the memory, and finally, the logic is activated by a start-up process.

Configuration is automatically initiated on power-up unless it is delayed by the user, as described below. The configuration process can also be initiated by asserting $\overline{\text{PROGRAM}}$.

The end of the memory-clearing phase is signalled by $\overline{\text{INIT}}$ going High, and the completion of the entire process is signalled by DONE going High.

The power-up timing of configuration signals is shown in Figure 19. The corresponding timing characteristics are listed in Table 10.

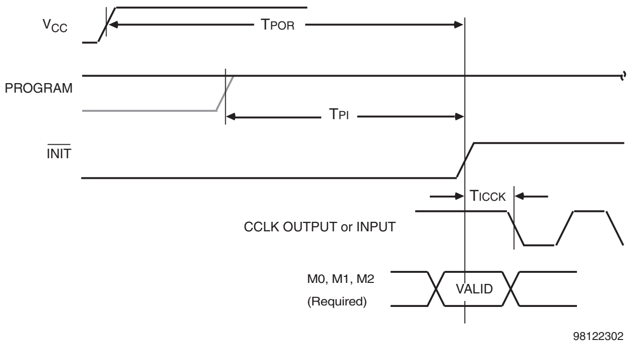


Figure 19: **Power-Up Timing Configuration Signals**

Table 10: **Power-up Timing Characteristics**

Description	Symbol	Value	Units
Power-on Reset	T_{POR}	2.0	ms, max
Program Latency	T_{PL}	100.0	µs, max
CCLK (output) Delay	T_{ICCK}	0.5	µs, min
		4.0	µs, max
Program Pulse Width	$T_{PROGRAM}$	300	ns, min

Delaying Configuration

$\overline{\text{INIT}}$ can be held Low using an open-drain driver. An open-drain is required since $\overline{\text{INIT}}$ is a bidirectional open-drain pin that is held Low by the FPGA while the configuration memory is being cleared. Extending the time that the pin is Low causes the configuration sequencer to wait. Thus, configuration is delayed by preventing entry into the phase where data is loaded.

Start-Up Sequence

The default Start-up sequence is that one CCLK cycle after DONE goes High, the global 3-state signal (GTS) is released. This permits device outputs to turn on as necessary.

One CCLK cycle later, the Global Set/Reset (GSR) and Global Write Enable (GWE) signals are released. This permits the internal storage elements to begin changing state in response to the logic and the user clock.

The relative timing of these events can be changed. In addition, the GTS, GSR, and GWE events can be made dependent on the DONE pins of multiple devices all going High, forcing the devices to start in synchronism. The sequence can also be paused at any stage until lock has been achieved on any or all DLLs.

Virtex DC Characteristics

Absolute Maximum Ratings

Symbol	Description(1)			Units
V_{CCINT}	Supply voltage relative to GND(2)		–0.5 to 3.0	V
V_{CCO}	Supply voltage relative to GND(2)		–0.5 to 4.0	V
V_{REF}	Input Reference Voltage		–0.5 to 3.6	V
V_{IN}	Input voltage relative to GND(3)	Using V_{REF}	–0.5 to 3.6	V
		Internal threshold	–0.5 to 5.5	V
V_{TS}	Voltage applied to 3-state output		–0.5 to 5.5	V
V_{CC}	Longest Supply Voltage Rise Time from 1V-2.375V		50	ms
T_{STG}	Storage temperature (ambient)		–65 to +150	°C
T_J	Junction temperature(4)	Plastic Packages	+125	°C

Notes:

1. Stresses beyond those listed under Absolute Maximum Ratings can cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time can affect device reliability.
2. Power supplies can turn on in any order.
3. For protracted periods (e.g., longer than a day), V_{IN} should not exceed V_{CCO} by more than 3.6 V.
4. For soldering guidelines and thermal considerations, see the "Device Packaging" information on www.xilinx.com.

Recommended Operating Conditions

Symbol	Description		Min	Max	Units
V_{CCINT}(1)	Input Supply voltage relative to GND, T_J = 0 °C to +85°C	Commercial	2.5 – 5%	2.5 + 5%	V
	Input Supply voltage relative to GND, T_J = –40°C to +100°C	Industrial	2.5 – 5%	2.5 + 5%	V
V_{CCO}(4)	Supply voltage relative to GND, T_J = 0 °C to +85°C	Commercial	1.4	3.6	V
	Supply voltage relative to GND, T_J = –40°C to +100°C	Industrial	1.4	3.6	V
T_{IN}	Input signal transition time			250	ns

Notes:

1. Correct operation is guaranteed with a minimum V_{CCINT} of 2.375 V (Nominal V_{CCINT} –5%). Below the minimum value, all delay parameters increase by 3% for each 50-mV reduction in V_{CCINT} below the specified range.
2. At junction temperatures above those listed as Operating Conditions, delay parameters do increase. Please refer to the TRCE report.
3. Input and output measurement threshold is ~50% of V_{CC}.
4. Min and Max values for V_{CCO} are I/O Standard dependant.

Power-On Power Supply Requirements

Xilinx FPGAs require a certain amount of supply current during power-on to insure proper device operation. The actual current consumed depends on the power-on ramp rate of the power supply. This is the time required to reach the nominal power supply voltage of the device(1) from 0 V. The current is highest at the fastest suggested ramp rate (0 V to nominal voltage in 2 ms) and is lowest at the slowest allowed ramp rate (0 V to nominal voltage in 50 ms). For more details on power supply requirements, see Application Note XAPP158 on www.xilinx.com.

Product	Description(2)	Current Requirement(1,3)
Virtex Family, Commercial Grade	Minimum required current supply	500 mA
Virtex Family, Industrial Grade	Minimum required current supply	2 A

Notes:

1. Ramp rate used for this specification is from 0 - 2.7 VDC. Peak current occurs on or near the internal power-on reset threshold of 1.0V and lasts for less than 3 ms.
2. Devices are guaranteed to initialize properly with the minimum current available from the power supply as noted above.
3. Larger currents can result if ramp rates are forced to be faster.

DC Input and Output Levels

Values for V_{IL} and V_{IH} are recommended input voltages. Values for I_{OL} and I_{OH} are guaranteed output currents over the recommended operating conditions at the V_{OL} and V_{OH} test points. Only selected standards are tested. These are chosen to ensure that all standards meet their specifications. The selected standards are tested at minimum V_{CCO} for each standard with the respective V_{OL} and V_{OH} voltage levels shown. Other standards are sample tested.

Input/Output Standard	V_{IL}		V_{IH}		V_{OL}	V_{OH}	I_{OL}	I_{OH}
	V, min	V, max	V, min	V, max	V, Max	V, Min	mA	mA
LVTTL(1)	– 0.5	0.8	2.0	5.5	0.4	2.4	24	–24
LVCMOS2	– 0.5	.7	1.7	5.5	0.4	1.9	12	–12
PCI, 3.3 V	– 0.5	44% V_{CCINT}	60% V_{CCINT}	V_{CCO} + 0.5	10% V_{CCO}	90% V_{CCO}	Note 2	Note 2
PCI, 5.0 V	– 0.5	0.8	2.0	5.5	0.55	2.4	Note 2	Note 2
GTL	– 0.5	V_{REF} – 0.05	V_{REF} + 0.05	3.6	0.4	n/a	40	n/a
GTL+	– 0.5	V_{REF} – 0.1	V_{REF} + 0.1	3.6	0.6	n/a	36	n/a
HSTL I(3)	– 0.5	V_{REF} – 0.1	V_{REF} + 0.1	3.6	0.4	V_{CCO} – 0.4	8	–8
HSTL III	– 0.5	V_{REF} – 0.1	V_{REF} + 0.1	3.6	0.4	V_{CCO} – 0.4	24	–8
HSTL IV	– 0.5	V_{REF} – 0.1	V_{REF} + 0.1	3.6	0.4	V_{CCO} – 0.4	48	–8
SSTL3 I	– 0.5	V_{REF} – 0.2	V_{REF} + 0.2	3.6	V_{REF} – 0.6	V_{REF} + 0.6	8	–8
SSTL3 II	– 0.5	V_{REF} – 0.2	V_{REF} + 0.2	3.6	V_{REF} – 0.8	V_{REF} + 0.8	16	–16
SSTL2 I	– 0.5	V_{REF} – 0.2	V_{REF} + 0.2	3.6	V_{REF} – 0.61	V_{REF} + 0.61	7.6	–7.6
SSTL2 II	– 0.5	V_{REF} – 0.2	V_{REF} + 0.2	3.6	V_{REF} – 0.80	V_{REF} + 0.80	15.2	–15.2
CTT	– 0.5	V_{REF} – 0.2	V_{REF} + 0.2	3.6	V_{REF} – 0.4	V_{REF} + 0.4	8	–8
AGP	– 0.5	V_{REF} – 0.2	V_{REF} + 0.2	3.6	10% V_{CCO}	90% V_{CCO}	Note 2	Note 2

Notes:

1. V_{OL} and V_{OH} for lower drive currents are sample tested.
2. Tested according to the relevant specifications.
3. DC input and output levels for HSTL18 (HSTL I/O standard with V_{CCO} of 1.8 V) are provided in an HSTL white paper on www.xilinx.com.

Virtex Switching Characteristics

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation net list. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Virtex devices unless otherwise noted.

IOB Input Switching Characteristics

Input delays associated with the pad are specified for LVTTL levels. For other standards, adjust the delays with the values shown in , page 6.

Description	Device	Symbol	Speed Grade				Units
			Min	-6	-5	-4	
Propagation Delays							
Pad to I output, no delay	All	T_{IOPI}	0.39	0.8	0.9	1.0	ns, max
Pad to I output, with delay	XCV50	T_{IOPID}	0.8	1.5	1.7	1.9	ns, max
	XCV100		0.8	1.5	1.7	1.9	ns, max
	XCV150		0.8	1.5	1.7	1.9	ns, max
	XCV200		0.8	1.5	1.7	1.9	ns, max
	XCV300		0.8	1.5	1.7	1.9	ns, max
	XCV400		0.9	1.8	2.0	2.3	ns, max
	XCV600		0.9	1.8	2.0	2.3	ns, max
	XCV800		1.1	2.1	2.4	2.7	ns, max
	XCV1000		1.1	2.1	2.4	2.7	ns, max
Pad to output IQ via transparent latch, no delay	All	T_{IOPLI}	0.8	1.6	1.8	2.0	ns, max
Pad to output IQ via transparent latch, with delay	XCV50	T_{IOPLID}	1.9	3.7	4.2	4.8	ns, max
	XCV100		1.9	3.7	4.2	4.8	ns, max
	XCV150		2.0	3.9	4.3	4.9	ns, max
	XCV200		2.0	4.0	4.4	5.1	ns, max
	XCV300		2.0	4.0	4.4	5.1	ns, max
	XCV400		2.1	4.1	4.6	5.3	ns, max
	XCV600		2.1	4.2	4.7	5.4	ns, max
	XCV800		2.2	4.4	4.9	5.6	ns, max
	XCV1000		2.3	4.5	5.1	5.8	ns, max
Sequential Delays							
Clock CLK	All						
Minimum Pulse Width, High		T_{CH}	0.8	1.5	1.7	2.0	ns, min
Minimum Pulse Width, Low		T_{CL}	0.8	1.5	1.7	2.0	ns, min
Clock CLK to output IQ		T_{IOCKIQ}	0.2	0.7	0.7	0.8	ns, max

IOB Output Switching Characteristics Standard Adjustments

Output delays terminating at a pad are specified for LVTTL with 12 mA drive and fast slew rate. For other standards, adjust the delays by the values shown.

Description	Symbol	Standard[1]	Speed Grade				Units
			Min	-6	-5	-4	
Output Delay Adjustments							
Standard-specific adjustments for output delays terminating at pads (based on standard capacitive load, Csl)	T_{OLVTTL_S2}	LVTTL, Slow, 2 mA	4.2	14.7	15.8	17.0	ns
	T_{OLVTTL_S4}	4 mA	2.5	7.5	8.0	8.6	ns
	T_{OLVTTL_S6}	6 mA	1.8	4.8	5.1	5.6	ns
	T_{OLVTTL_S8}	8 mA	1.2	3.0	3.3	3.5	ns
	T_{OLVTTL_S12}	12 mA	1.0	1.9	2.1	2.2	ns
	T_{OLVTTL_S16}	16 mA	0.9	1.7	1.9	2.0	ns
	T_{OLVTTL_S24}	24 mA	0.8	1.3	1.4	1.6	ns
	T_{OLVTTL_F2}	LVTTL, Fast, 2mA	1.9	13.1	14.0	15.1	ns
	T_{OLVTTL_F4}	4 mA	0.7	5.3	5.7	6.1	ns
	T_{OLVTTL_F6}	6 mA	0.2	3.1	3.3	3.6	ns
	T_{OLVTTL_F8}	8 mA	0.1	1.0	1.1	1.2	ns
	T_{OLVTTL_F12}	12 mA	0	0	0	0	ns
	T_{OLVTTL_F16}	16 mA	–0.10	–0.05	–0.05	–0.05	ns
	T_{OLVTTL_F24}	24 mA	–0.10	–0.20	–0.21	–0.23	ns
	$T_{OLVCMOS2}$	LVCMOS2	0.10	0.10	0.11	0.12	ns
	T_{OPCI33_3}	PCI, 33 MHz, 3.3 V	0.50	2.3	2.5	2.7	ns
	T_{OPCI33_5}	PCI, 33 MHz, 5.0 V	0.40	2.8	3.0	3.3	ns
	T_{OPCI66_3}	PCI, 66 MHz, 3.3 V	0.10	–0.40	–0.42	–0.46	ns
	T_{OGTL}	GTL	0.6	0.50	0.54	0.6	ns
	T_{OGTLP}	GTL+	0.7	0.8	0.9	1.0	ns
	T_{OHSTL_I}	HSTL I	0.10	–0.50	–0.53	–0.5	ns
	T_{OHSTL_III}	HSTL III	–0.10	–0.9	–0.9	–1.0	ns
	T_{OHSTL_IV}	HSTL IV	–0.20	–1.0	–1.0	–1.1	ns
	T_{OSSTL2_I}	SSTL2 I	–0.10	–0.50	–0.53	–0.5	ns
	T_{OSSLT2_II}	SSTL2 II	–0.20	–0.9	–0.9	–1.0	ns
	T_{OSSTL3_I}	SSTL3 I	–0.20	–0.50	–0.53	–0.5	ns
	T_{OSSTL3_II}	SSTL3 II	–0.30	–1.0	–1.0	–1.1	ns
	T_{OCTT}	CTT	0	–0.6	–0.6	–0.6	ns
	T_{OAGP}	AGP	0	–0.9	–0.9	–1.0	ns

Notes:

1. Output timing is measured at 1.4 V with 35 pF external capacitive load for LVTTL. For other I/O standards and different loads, see Table 2 and Table 3.

CLB Arithmetic Switching Characteristics

Setup times not listed explicitly can be approximated by decreasing the combinatorial delays by the setup time adjustment listed. Precise values are provided by the timing analyzer.

Description	Symbol	Speed Grade				Units
		Min	-6	-5	-4	
Combinatorial Delays						
F operand inputs to X via XOR	T_{OPX}	0.37	0.8	0.9	1.0	ns, max
F operand input to XB output	T_{OPXB}	0.54	1.1	1.3	1.4	ns, max
F operand input to Y via XOR	T_{OPY}	0.8	1.5	1.7	2.0	ns, max
F operand input to YB output	T_{OPYB}	0.8	1.5	1.7	2.0	ns, max
F operand input to COUT output	T_{OPCYF}	0.6	1.2	1.3	1.5	ns, max
G operand inputs to Y via XOR	T_{OPGY}	0.46	1.0	1.1	1.2	ns, max
G operand input to YB output	T_{OPGYB}	0.8	1.6	1.8	2.1	ns, max
G operand input to COUT output	T_{OPCYG}	0.7	1.3	1.4	1.6	ns, max
BX initialization input to COUT	T_{BXCY}	0.41	0.9	1.0	1.1	ns, max
CIN input to X output via XOR	T_{CINX}	0.21	0.41	0.46	0.53	ns, max
CIN input to XB	T_{CINXB}	0.02	0.04	0.05	0.06	ns, max
CIN input to Y via XOR	T_{CINY}	0.23	0.46	0.52	0.6	ns, max
CIN input to YB	T_{CINYB}	0.23	0.45	0.51	0.6	ns, max
CIN input to COUT output	T_{BYP}	0.05	0.09	0.10	0.11	ns, max
Multiplier Operation						
F1/2 operand inputs to XB output via AND	T_{FANDXB}	0.18	0.36	0.40	0.46	ns, max
F1/2 operand inputs to YB output via AND	T_{FANDYB}	0.40	0.8	0.9	1.1	ns, max
F1/2 operand inputs to COUT output via AND	T_{FANDCY}	0.22	0.43	0.48	0.6	ns, max
G1/2 operand inputs to YB output via AND	T_{GANDYB}	0.25	0.50	0.6	0.7	ns, max
G1/2 operand inputs to COUT output via AND	T_{GANDCY}	0.07	0.13	0.15	0.17	ns, max
Setup and Hold Times before/after Clock CLK(1)	Setup Time / Hold Time					
CIN input to FFX	T_{CCKX}/T_{CKCX}	0.50 / 0	1.0 / 0	1.2 / 0	1.3 / 0	ns, min
CIN input to FFY	T_{CCKY}/T_{CKCY}	0.53 / 0	1.1 / 0	1.2 / 0	1.4 / 0	ns, min

Notes:

1. A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.

Virtex Pin-to-Pin Output Parameter Guidelines

All devices are 100% functionally tested. Listed below are representative values for typical pin locations and normal clock loading. Values are expressed in nanoseconds unless otherwise noted.

Global Clock Input to Output Delay for LVTTL, 12 mA, Fast Slew Rate, *with* DLL

Description	Symbol	Device	Speed Grade				Units
			Min	-6	-5	-4	
LVTTL Global Clock Input to Output Delay using Output Flip-flop, 12 mA, Fast Slew Rate, *with* DLL. For data *output* with different standards, adjust delays with the values shown in Output Delay Adjustments.	$T_{ICKOFDLL}$	XCV50	1.0	3.1	3.3	3.6	ns, max
		XCV100	1.0	3.1	3.3	3.6	ns, max
		XCV150	1.0	3.1	3.3	3.6	ns, max
		XCV200	1.0	3.1	3.3	3.6	ns, max
		XCV300	1.0	3.1	3.3	3.6	ns, max
		XCV400	1.0	3.1	3.3	3.6	ns, max
		XCV600	1.0	3.1	3.3	3.6	ns, max
		XCV800	1.0	3.1	3.3	3.6	ns, max
		XCV1000	1.0	3.1	3.3	3.6	ns, max

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Output timing is measured at 1.4 V with 35 pF external capacitive load for LVTTL. The 35 pF load does not apply to the Min values. For other I/O standards and different loads, see Table 2 and Table 3.
3. DLL output jitter is already included in the timing calculation.

Global Clock Input-to-Output Delay for LVTTL, 12 mA, Fast Slew Rate, *without* DLL

Description	Symbol	Device	Speed Grade				Units
			Min	-6	-5	-4	
LVTTL Global Clock Input to Output Delay using Output Flip-flop, 12 mA, Fast Slew Rate, *without* DLL. For data *output* with different standards, adjust delays with the values shown in Input and Output Delay Adjustments. For I/O standards requiring V_{REF}, such as GTL, GTL+, SSTL, HSTL, CTT, and AGO, an additional 600 ps must be added.	T_{ICKOF}	XCV50	1.5	4.6	5.1	5.7	ns, max
		XCV100	1.5	4.6	5.1	5.7	ns, max
		XCV150	1.5	4.7	5.2	5.8	ns, max
		XCV200	1.5	4.7	5.2	5.8	ns, max
		XCV300	1.5	4.7	5.2	5.9	ns, max
		XCV400	1.5	4.8	5.3	6.0	ns, max
		XCV600	1.6	4.9	5.4	6.0	ns, max
		XCV800	1.6	4.9	5.5	6.2	ns, max
		XCV1000	1.7	5.0	5.6	6.3	ns, max

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Output timing is measured at 1.4 V with 35 pF external capacitive load for LVTTL. The 35 pF load does not apply to the Min values. For other I/O standards and different loads, see Table 2 and Table 3.

Virtex Pinout Information

Pinout Tables

See **www.xilinx.com** for updates or additional pinout information. For convenience, Table 2, Table 3 and Table 4 list the locations of special-purpose and power-supply pins. Pins not listed are either user I/Os or not connected, depending on the device/package combination. See the Pinout Diagrams starting on page 17 for any pins not listed for a particular part/package combination.

Table 2: **Virtex Pinout Tables (Chip-Scale and QFP Packages)**

Pin Name	Device	CS144	TQ144	PQ/HQ240
GCK0	All	K7	90	92
GCK1	All	M7	93	89
GCK2	All	A7	19	210
GCK3	All	A6	16	213
M0	All	M1	110	60
M1	All	L2	112	58
M2	All	N2	108	62
CCLK	All	B13	38	179
PROGRAM	All	L12	72	122
DONE	All	M12	74	120
INIT	All	L13	71	123
BUSY/DOUT	All	C11	39	178
D0/DIN	All	C12	40	177
D1	All	E10	45	167
D2	All	E12	47	163
D3	All	F11	51	156
D4	All	H12	59	145
D5	All	J13	63	138
D6	All	J11	65	134
D7	All	K10	70	124
WRITE	All	C10	32	185
CS	All	D10	33	184
TDI	All	A11	34	183
TDO	All	A12	36	181
TMS	All	B1	143	2
TCK	All	C3	2	239
V_{CCINT}	All	A9, B6, C5, G3, G12, M5, M9, N6	10, 15, 25, 57, 84, 94, 99, 126	16, 32, 43, 77, 88, 104, 137, 148, 164, 198, 214, 225

Table 2: **Virtex Pinout Tables (Chip-Scale and QFP Packages)** ***(Continued)***

Pin Name	Device	CS144	TQ144	PQ/HQ240
V_{REF}, Bank 3 (V_{REF} pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V_{REF} pins are general I/O.	XCV50	H11, K12	60, 68	130, 144
	XCV100/150	... + J10	... + 66	... + 133
	XCV200/300	N/A	N/A	... + 126
	XCV400	N/A	N/A	... + 147
	XCV600	N/A	N/A	... + 132
	XCV800	N/A	N/A	... + 140
V_{REF}, Bank 4 (V_{REF} pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V_{REF} pins are general I/O.	XCV50	L8, L10	79, 87	97, 111
	XCV100/150	... + N10	... + 81	... + 108
	XCV200/300	N/A	N/A	... + 115
	XCV400	N/A	N/A	... + 94
	XCV600	N/A	N/A	... + 109
	XCV800	N/A	N/A	... + 101
V_{REF}, Bank 5 (V_{REF} pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V_{REF} pins are general I/O.	XCV50	L4, L6	96, 104	70, 84
	XCV100/150	... + N4	... + 102	... + 73
	XCV200/300	N/A	N/A	... + 66
	XCV400	N/A	N/A	... + 87
	XCV600	N/A	N/A	... + 72
	XCV800	N/A	N/A	... + 80

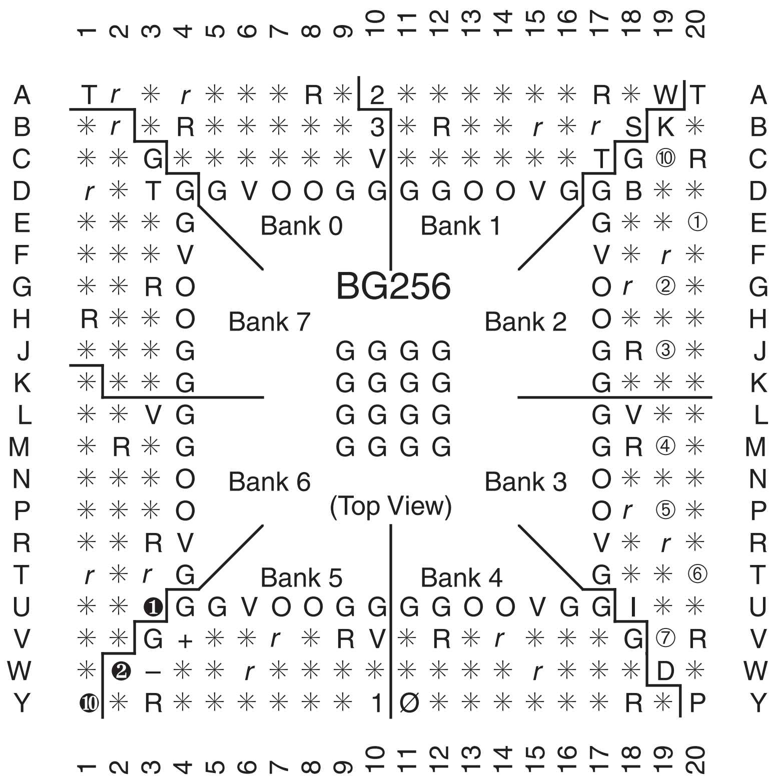
Table 4: **Virtex Pinout Tables (Fine-Pitch BGA)**

Pin Name	Device	FG256	FG456	FG676	FG680
GCK0	All	N8	W12	AA14	AW19
GCK1	All	R8	Y11	AB13	AU22
GCK2	All	C9	A11	C13	D21
GCK3	All	B8	C11	E13	A20
M0	All	N3	AB2	AD4	AT37
M1	All	P2	U5	W7	AU38
M2	All	R3	Y4	AB6	AT35
CCLK	All	D15	B22	D24	E4
PROGRAM	All	P15	W20	AA22	AT5
DONE	All	R14	Y19	AB21	AU5
INIT	All	N15	V19	Y21	AU2
BUSY/DOUT	All	C15	C21	E23	E3
D0/DIN	All	D14	D20	F22	C2
D1	All	E16	H22	K24	P4
D2	All	F15	H20	K22	P3
D3	All	G16	K20	M22	R1
D4	All	J16	N22	R24	AD3
D5	All	M16	R21	U23	AG2
D6	All	N16	T22	V24	AH1
D7	All	N14	Y21	AB23	AR4
WRITE	All	C13	A20	C22	B4
CS	All	B13	C19	E21	D5
TDI	All	A15	B20	D22	B3
TDO	All	B14	A21	C23	C4
TMS	All	D3	D3	F5	E36
TCK	All	C4	C4	E6	C36
DXN	All	R4	Y5	AB7	AV37
DXP	All	P4	V6	Y8	AU35

Table 4: **Virtex Pinout Tables (Fine-Pitch BGA)** ***(Continued)***

Pin Name	Device	FG256	FG456	FG676	FG680
V_{REF}, Bank 1 (VREF pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V_{REF} pins are general I/O.	XCV50	B9, C11	N/A	N/A	N/A
	XCV100/150	... + E11	A18, B13, E14	N/A	N/A
	XCV200/300	... + A14	... + A19	N/A	N/A
	XCV400	N/A	N/A	A14, C20, C21, D15, G16	N/A
	XCV600	N/A	N/A	... + B19	B6, B8, B18, D11, D13, D17
	XCV800	N/A	N/A	... + A17	... + B14
	XCV1000	N/A	N/A	N/A	... + B5
V_{REF}, Bank 2 (V_{REF} pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V_{REF} pins are general I/O.	XCV50	F13, H13	N/A	N/A	N/A
	XCV100/150	... + F14	F21, H18, K21	N/A	N/A
	XCV200/300	... + E13	... + D22	N/A	N/A
	XCV400	N/A	N/A	F24, H23, K20, M23, M26	N/A
	XCV600	N/A	N/A	... + G26	G1, H4, J1, L2, V5, W3
	XCV800	N/A	N/A	... + K25	... + N1
	XCV1000	N/A	N/A	N/A	... + D2
V_{REF}, Bank 3 (V_{REF} pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V_{REF} pins are general I/O.	XCV50	K16, L14	N/A	N/A	N/A
	XCV100/150	... + L13	N21, R19, U21	N/A	N/A
	XCV200/300	... + M13	... + U20	N/A	N/A
	XCV400	N/A	N/A	R23, R25, U21, W22, W23	N/A
	XCV600	N/A	N/A	... + W26	AC1, AJ2, AK3, AL4, AR1, Y1
	XCV800	N/A	N/A	... + U25	... + AF3
	XCV1000	N/A	N/A	N/A	... + AP4

BG256 Pin Function Diagram



	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	
A	T	*r*	✳	*r*	✳	✳	✳	R	✳	2	✳	✳	✳	✳	✳	✳	R	✳	W	T	A
B	✳	*r*	✳	R	✳	✳	✳	✳	✳	3	✳	R	✳	✳	*r*	✳	*r*	S	K	✳	B
C	✳	✳	G	✳	✳	✳	✳	✳	✳	V	✳	✳	✳	✳	✳	✳	T	G	⑩	R	C
D	*r*	✳	T	G	G	V	O	O	G	G	G	G	O	O	V	G	G	B	✳	✳	D
E	✳	✳	✳	G													G	✳	✳	①	E
F	✳	✳	✳	V													V	✳	*r*	✳	F
G	✳	✳	R	O													O	*r*	②	✳	G
H	R	✳	✳	O													O	✳	✳	✳	H
J	✳	✳	✳	G					G	G	G	G					G	R	③	✳	J
K	✳	✳	✳	G					G	G	G	G					G	✳	✳	✳	K
L	✳	✳	V	G					G	G	G	G					G	V	✳	✳	L
M	✳	R	✳	G					G	G	G	G					G	R	④	✳	M
N	✳	✳	✳	O													O	✳	✳	✳	N
P	✳	✳	✳	O													O	*r*	⑤	✳	P
R	✳	✳	R	V													V	✳	*r*	✳	R
T	*r*	✳	*r*	G													G	✳	✳	⑥	T
U	✳	✳	❶	G	G	V	O	O	G	G	G	G	O	O	V	G	G	I	✳	✳	U
V	✳	✳	G	+	✳	✳	*r*	✳	R	V	✳	R	✳	*r*	✳	✳	✳	G	⑦	R	V
W	✳	❷	–	✳	✳	*r*	✳	✳	✳	✳	✳	✳	✳	✳	*r*	✳	✳	✳	D	✳	W
Y	❿	✳	R	✳	✳	✳	✳	✳	✳	1	Ø	✳	✳	✳	✳	✳	✳	R	✳	P	Y
	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	

DS003_18_100300

Figure 4: **BG256 Pin Function Diagram**

BG560 Pin Function Diagram

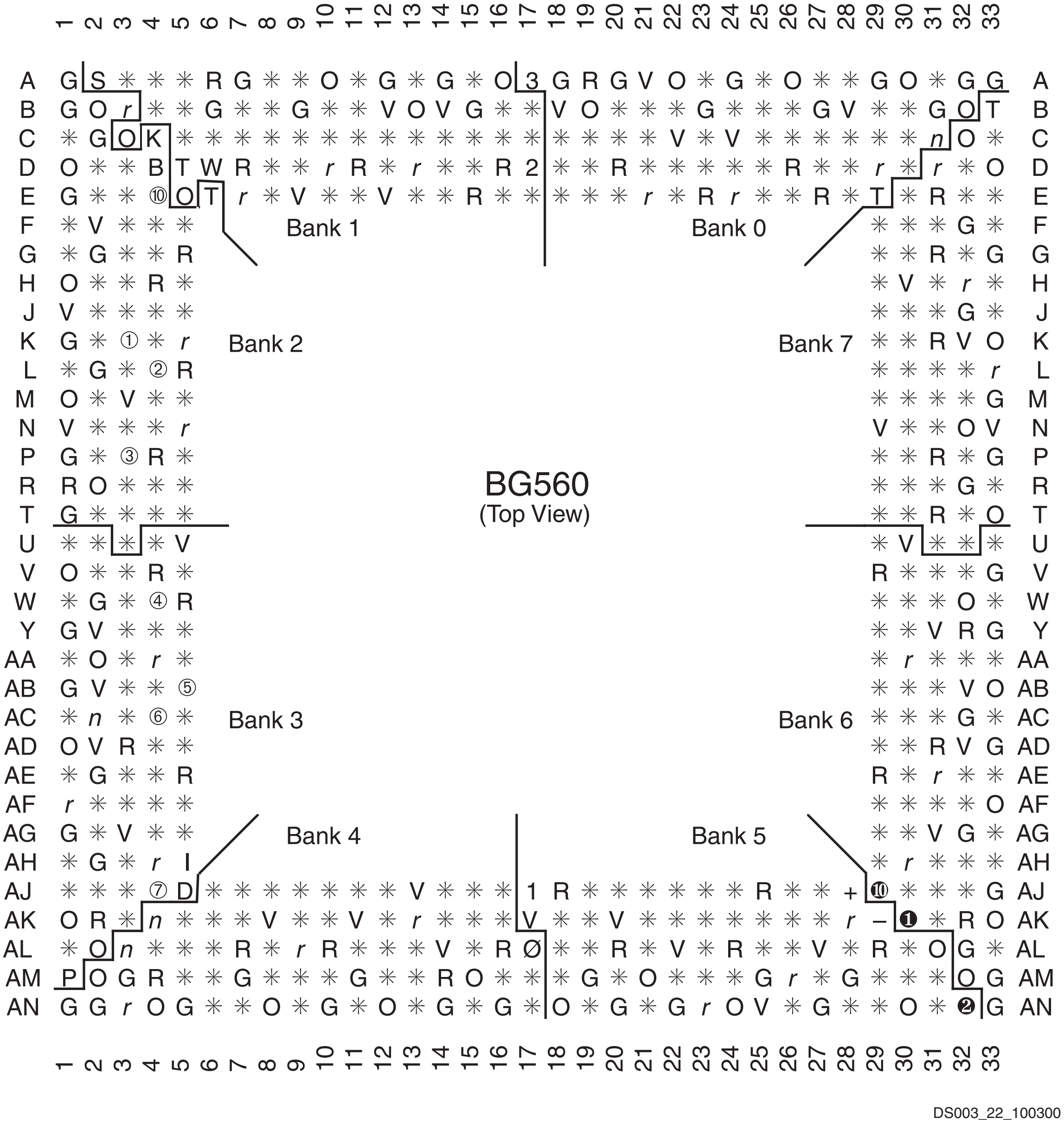


Figure 7: **BG560 Pin Function Diagram**